Applic. No. 09/922,479
Reply to Office Action dated November 1, 2007
Amendment dated February 1, 2008
Replacement Sheet

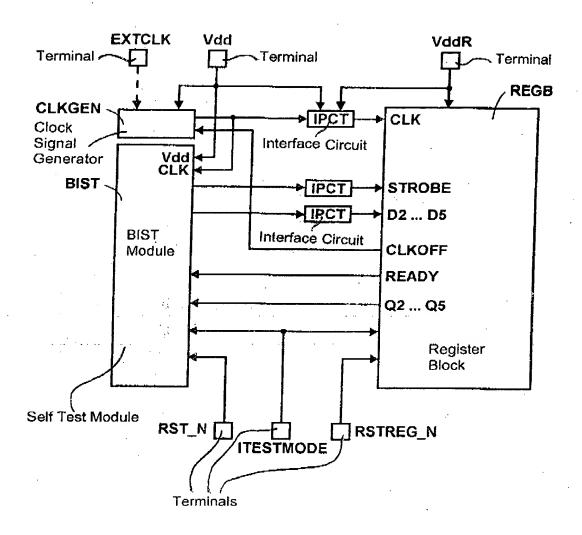


FIG 1

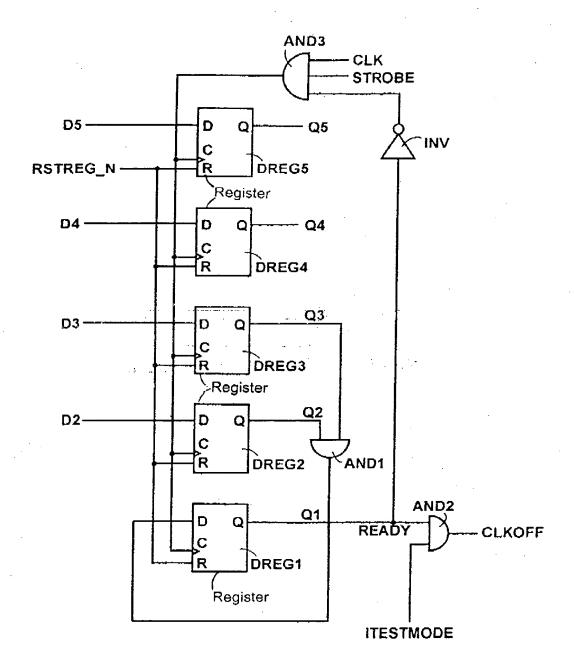


FIG 2

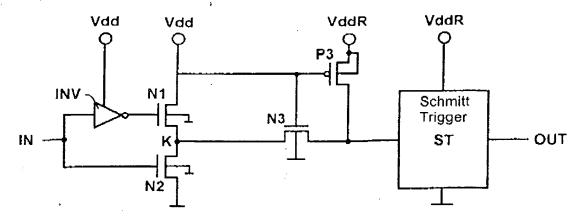


FIG 3A

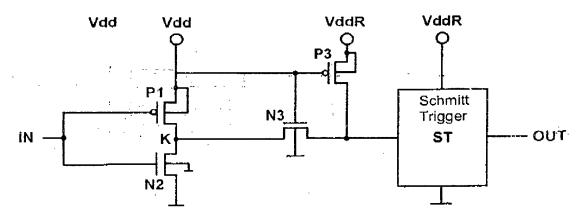
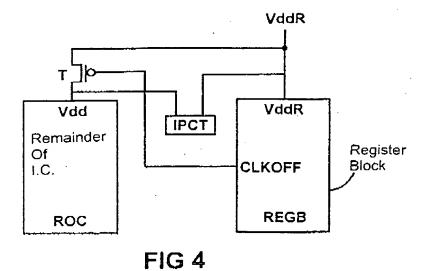
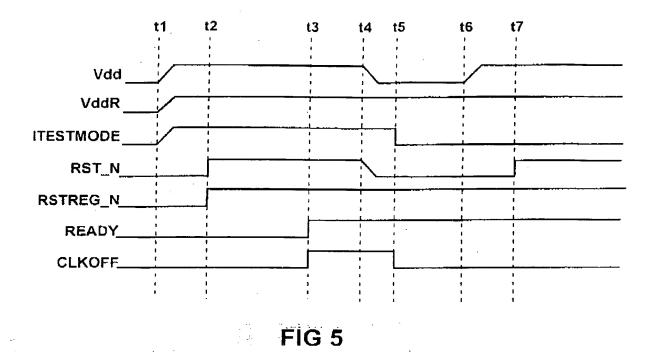


FIG 3B





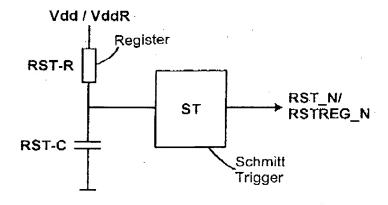


FIG 6

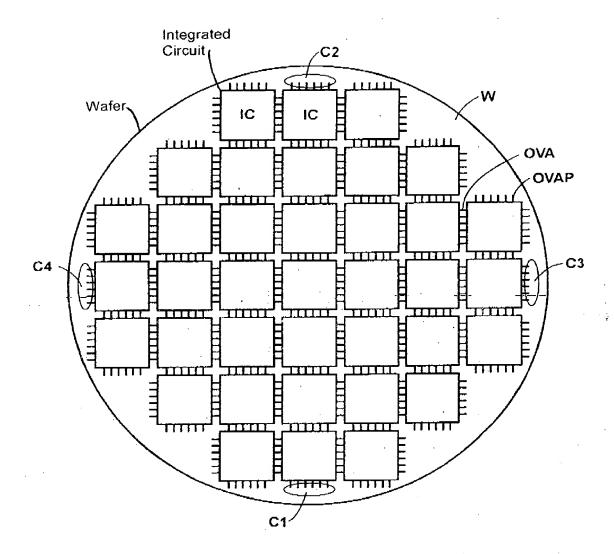


FIG 7

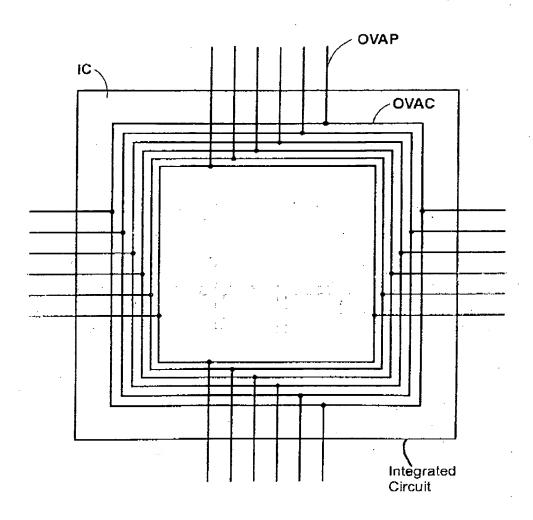
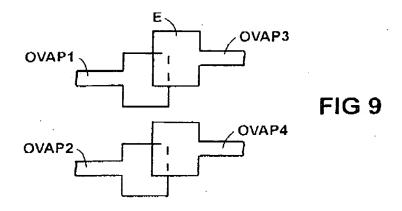
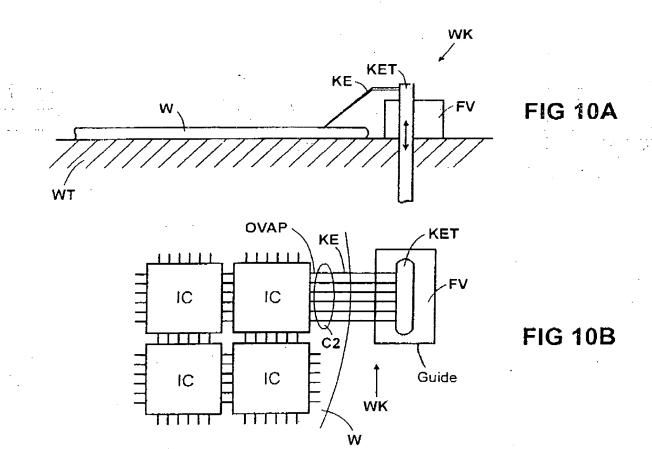
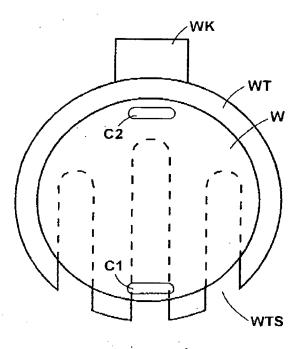


FIG 8

7/14







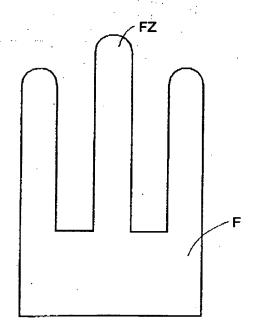


FIG 11A

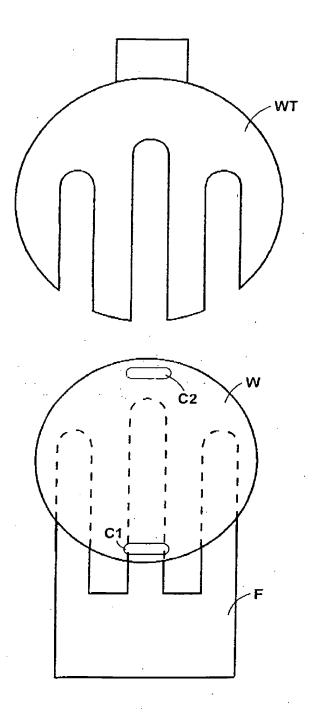


FIG 11C

Applic. No. 09/922,479

Reply to Office Action dated November 1, 2007 Amendment dated February 1, 2008 Replacement Sheet 11/14 TB Test Box -Wafer Carriers WK W Terminals CM REGRST VddR ITESTMODE **Control Device**

FIG 12

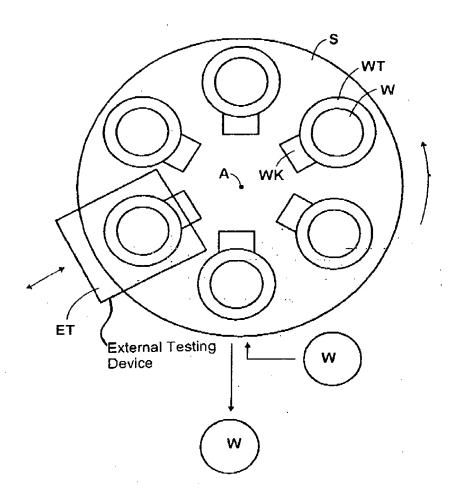
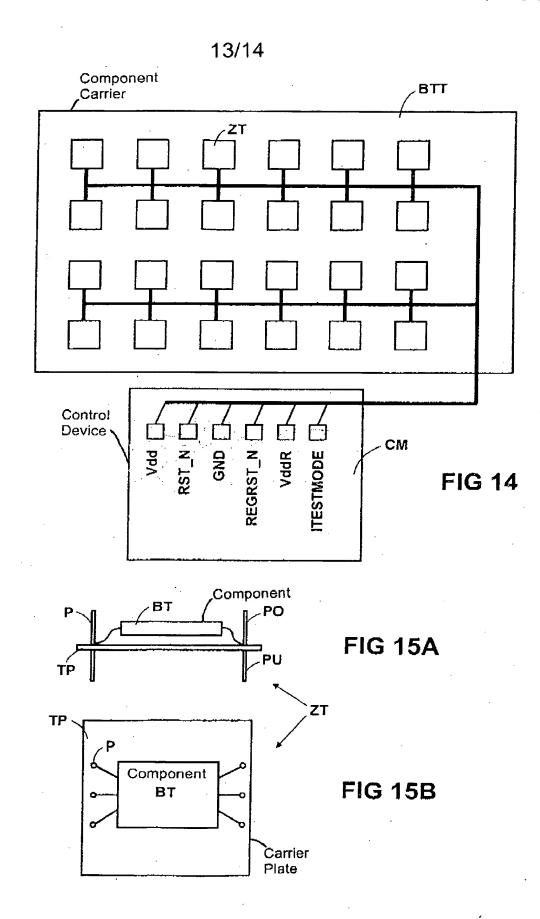


FIG 13



Applic. No. 09/922,479

Reply to Office Action dated November 1, 2007 14/14 Amendment dated February 1, 2008 **New Sheet** 100 **FIG.16** providing a plurality of integrated circuits on at least one wafer providing each integrated circuit with a self-test device providing a self-test control device that causes performance of the test of the integrated circuit either temporarily storing a plurality of integrated circuits or moving the self-test control device together with the plurality of integrated circuits while simultaneously at least partially completing the testing of the plurality of integrated circuits with the self-test devices with each self-test device, writing data into a test result memory on the integrated circuit with the self-test device 150 taking at least parts of an integrated circuit out of operation after the parts have been tested by the self-test device on the integrated circuit by: preventing a clock signal from being supplied, which is needed to operate the integrated circuit, to the parts of the integrated circuit, and/or by discontinuing a supply voltage, which supplies the integrated circuit with power, to the parts of the integrated circuit 160 after testing the integrated circuit with the self-test device, taking out of operation. components of the integrated circuit that are not needed to continue to store the data in the test result memory 170 after completing the testing, then connecting an integrated circuit to an external testing device that performs a function selected from the group consisting of reading out results of the test and evaluating the results of the test